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Notice of References Cited

09/667,630 Examiner 2662 Hanh Nguyen

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6377570B1	04-2002	Vaziri et al.	370/352
	В	US-6614783 B1	09-2003	Sonesh et al.	370/352
	C	US-6125177	09-2000	Whittaker	379/243
	D	US-6625139 B2	09-2003	Miloslavky et al.	370/352
	Е	US-6275490 B1	08-2001	Mattaway et al.	370/352
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	α					
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	Т					

NON-PATENT DOCUMENTS

*	Γ	
<u> </u>		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	Х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.